

Schedule of Accreditation

issued by

United Kingdom Accreditation Service

2 Pine Trees, Chertsey Lane, Staines-upon-Thames, TW18 3HR, UK

 <p>UKAS TESTING 2806</p> <p>Accredited to ISO/IEC 17025:2017</p>	<p>Reltech Limited</p> <p>Issue No: 017 Issue date: 11 September 2025</p>	
	<p>Cam Mills Lower Cam Dursley Gloucestershire GL11 5PW</p>	<p>Contact: Mr Paul Tuffin Tel: +44 (0)1453 541200 Fax: +44 (0)1453 545810 E-Mail: sales@reltech.co.uk Website: www.reltech.co.uk</p>
<p>Testing performed at the above address only</p>		

DETAIL OF ACCREDITATION

Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
ELECTRICAL AND ELECTRONIC COMPONENTS, INCLUDING SOLID STATE ELECTRONIC AND SEMICONDUCTOR DEVICES	<p>ENVIRONMENTAL TESTS (Non Explosive Items)</p> <p>HIGH/LOW TEMPERATURE</p> <p>Max Temp: + 200 °C Max Chamber Size: 0.36 m x 0.8 m x 0.45 m Minimum Temp: - 40 °C Max Chamber Size: 0.46 m x 0.60 m x 0.60 m</p>	<p>JEDEC Standard Specifications</p> <p>AEC-Q100-Rev J Standard to the extent covered in the JEDEC tests below</p> <p>JESD22 - A103E.1: July 2021 High Temperature Storage (HTS) Condition A: + 125 °C Condition B: + 150 °C Condition C: + 175 °C Condition D: + 200 °C Condition G: + 85 °C JESD22-A108G: Nov 2022 Including: High Temperature Operating Life (HTOL) Low Temperature Operating Life (LTOL) High Temperature Forward Bias (HTFB) High Temperature Reverse Bias (HTRB) High Temperature Gate Bias (HTGB)</p> <p>JESD22-A119: Oct 2015 Low Temperature Storage (LTS)</p>



2806
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ISO/IEC 17025:20175

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Issue No: 017 **Issue date:** 11 September 2025

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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
ELECTRICAL AND ELECTRONIC COMPONENTS, INCLUDING SOLID STATE ELECTRONIC AND SEMICONDUCTOR DEVICES (cont'd)	ENVIRONMENTAL TESTS (Non Explosive Items) (cont'd) TEMPERATURE CYCLING Max Temp: + 150 °C Max Temp: - 65 °C Max Chamber Size: 0.32 m x 0.23 m x 0.48 m TEMPERATURE/HUMIDITY Temp: + 85 °C Relative Humidity: 85 % RH Max Chamber Size: 0.6 m x 0.6 m x 0.6 m ELECTRICAL OPERATION AND MEASUREMENT DC Voltage: 200 mV to 1000 V	JEDEC Standard Specifications JESD22-A104F.01: Apr 2023 Conditions: A, B, C, G, H, I, J, K, L, M, N JESD22-A101D.01: Jan 2021 Steady State Temperature Humidity Bias Life Test (THB) Documented In-House Methods and Customer specified requirements
END		